

<b>Notice of References Cited</b>	Application/Control No. 10/728,836	Applicant(s)/Patent Under Reexamination VAID ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0139374	07-2004	Meaney et al.	714/048
*	B	US-6,052,819	04-2000	Barker et al.	714/776
*	C	US-6,457,154	09-2002	Chen et al.	714/768
*	D	US-6,460,154	10-2002	Duxbury, Guy M. A. F.	714/751
*	E	US-6,594,785	07-2003	Gilbertson et al.	714/48
*	F	US-6,948,094	09-2005	Schultz et al.	714/15
*	G	US-5,214,652	05-1993	Sutton, Arthur J.	714/10
*	H	US-5,249,212	09-1993	Covey et al.	714/765
*	I	US-6,536,000	03-2003	Jackson et al.	714/57
*	J	US-6,594,785	07-2003	Gilbertson et al.	714/48
*	K	US-6,751,756	06-2004	Hartnett et al.	714/54
*	L	US-6,823,476	11-2004	Williams et al.	714/25
*	M	US-2004/0153842	08-2004	Dickey et al.	714/042

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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